

<b>Notice of References Cited</b>	Application/Control No. 10/026,886	Applicant(s)/Patent Under Reexamination SHLAIN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,819,007	10-1998	Elghazzawi, Ziad F.	706/46
	B	US-6,014,461	01-2000	Hennessey et al.	382/195
	C	US-6,018,728	01-2000	Spence et al.	706/20
	D	US-6,092,059	07-2000	Straforini et al.	706/14
	E	US-6,421,654	07-2002	Gordon, Mirta Beatriz	706/16
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"DCS-1: A Fuzzy Logic Expert System for Automatic Defect Classification of Semiconductor Wafer Defects", Luria et al, Fuzzy Systems, 1994. IEEE World Congress on Computational Intelligence, Proc of the 3 <sup>rd</sup> IEEE Conference on 26-29 June 1994.
	V	"Automated Feature Extraction for Supervised Learning", by Laird et al, Evolutionary Computation, 1994. IEEE World Congress on Computational Intelligence., Proceedings of the First IEEE Conference on , 27-29 June 1994, Pages:674 - 679 vol.2
	W	"A Neural Network Approach for classifying test structure results" by Khera et al, Proc. IEEE 1989, Int. Conference on Microelectronic Test Structures, Vol. 2, No. 1, March 1989.
	X	"Adaptive Fuzzy Neural Trees" by Alois P. Heinz. In G. E. Lasker and X. Liu, editors, Advances in Intelligent Data Analysis, Proceedings of the IDA-95 Symposium, vol. I, pgs 70-74, Baden-Baden, Germany, Aug. 1995. The Int Institute for Advanced Studies

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	G	US-			
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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Genetic Learning of Fuzzy Rule-Based Classification Systems Cooperating with Fuzzy Reasoning Methods", by Cordon et al, International Journal of Intelligent Systems, vol. 13, pages 1025-1053 (1998).
	V	
	W	
	X	

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